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Details

Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I ² S, POR, PWM, WDT
Number of I/O	11
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 11x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	16-TSSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-16-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1302t016x0032abxuma1

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XMC1300 AB-Step

Microcontroller Series
for Industrial Applications

XMC1000 Family

ARM[®] Cortex[®]-M0
32-bit processor core

Data Sheet

V1.9 2017-03

Microcontrollers

- Configurable pad hysteresis

On-Chip Debug Support

- Support for debug features: 4 breakpoints, 2 watchpoints
- Various interfaces: ARM serial wire debug (SWD), single pin debug (SPD)

1.1 Ordering Information

The ordering code for an Infineon microcontroller provides an exact reference to a specific product. The code "XMC1<DDD>-<Z><PPP><T><FFFF>" identifies:

- <DDD> the derivatives function set
- <Z> the package variant
 - T: TSSOP
 - Q: VQFN
- <PPP> package pin count
- <T> the temperature range:
 - F: -40°C to 85°C
 - X: -40°C to 105°C
- <FFFF> the Flash memory size.

For ordering codes for the XMC1300 please contact your sales representative or local distributor.

This document describes several derivatives of the XMC1300 series, some descriptions may not apply to a specific product. Please see [Table 1](#).

For simplicity the term **XMC1300** is used for all derivatives throughout this document.

1.2 Device Types

These device types are available and can be ordered through Infineon's direct and/or distribution channels.

Table 1 Synopsis of XMC1300 Device Types

Derivative	Package	Flash Kbytes	SRAM Kbytes
XMC1301-T016F0008	PG-TSSOP-16-8	8	16
XMC1301-T016F0016	PG-TSSOP-16-8	16	16
XMC1301-T016F0032	PG-TSSOP-16-8	32	16
XMC1301-T016X0008	PG-TSSOP-16-8	8	16
XMC1301-T016X0016	PG-TSSOP-16-8	16	16
XMC1302-T016X0008	PG-TSSOP-16-8	8	16

Table 4 XMC1300 Chip Identification Number

Derivative	Value	Marking
XMC1301-T016F0008	00013032 01CF00FF 00001FF7 0000100F 00000C00 00001000 00003000 201ED083 _H	AB
XMC1301-T016F0016	00013032 01CF00FF 00001FF7 0000100F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1301-T016F0032	00013032 01CF00FF 00001FF7 0000100F 00000C00 00001000 00009000 201ED083 _H	AB
XMC1301-T016X0008	00013033 01CF00FF 00001FF7 0000100F 00000C00 00001000 00003000 201ED083 _H	AB
XMC1301-T016X0016	00013033 01CF00FF 00001FF7 0000100F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1302-T016X0008	00013033 01FF00FF 00001FF7 0000900F 00000C00 00001000 00003000 201ED083 _H	AB
XMC1302-T016X0016	00013033 01FF00FF 00001FF7 0000900F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1302-T016X0032	00013033 01FF00FF 00001FF7 0000900F 00000C00 00001000 00009000 201ED083 _H	AB
XMC1302-T028X0016	00013023 01FF00FF 00001FF7 0000900F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1301-T038F0008	00013012 01CF00FF 00001FF7 0000100F 00000C00 00001000 00003000 201ED083 _H	AB
XMC1301-T038F0016	00013012 01CF00FF 00001FF7 0000100F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1301-T038F0032	00013012 01CF00FF 00001FF7 0000100F 00000C00 00001000 00009000 201ED083 _H	AB
XMC1301-T038X0032	00013013 01CF00FF 00001FF7 0000100F 00000C00 00001000 00009000 201ED083 _H	AB
XMC1301-T038F0064	00013012 01CF00FF 00001FF7 0000100F 00000C00 00001000 00011000 201ED083 _H	AB
XMC1302-T038X0016	00013013 01FF00FF 00001FF7 0000900F 00000C00 00001000 00005000 201ED083 _H	AB
XMC1302-T038X0032	00013013 01FF00FF 00001FF7 0000900F 00000C00 00001000 00009000 201ED083 _H	AB
XMC1302-T038X0064	00013013 01FF00FF 00001FF7 0000900F 00000C00 00001000 00011000 201ED083 _H	AB

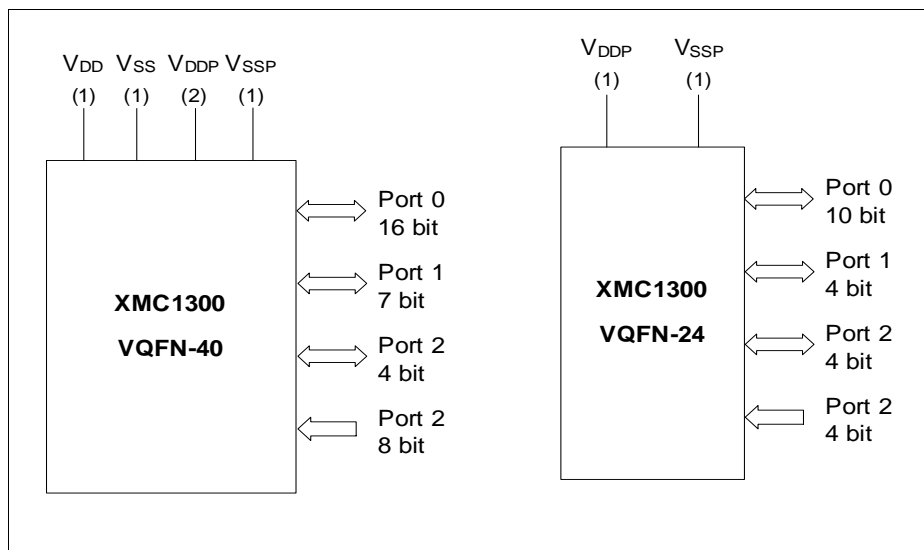


Figure 3 XMC1300 Logic Symbol for VQFN-24 and VQFN-40

2.2.1 Package Pin Summary

The following general building block is used to describe each pin:

Table 5 Package Pin Mapping Description

Function	Package A	Package B	...	Pad Type
Px.y	N	N		Pad Class

The table is sorted by the “Function” column, starting with the regular Port pins (Px.y), followed by the supply pins.

The following columns, titled with the supported package variants, lists the package pin number to which the respective function is mapped in that package.

The “Pad Type” indicates the employed pad type:

- STD_INOUT(standard bi-directional pads)
- STD_INOUT/AN (standard bi-directional pads with analog input)
- High Current (high current bi-directional pads)
- STD_IN/AN (standard input pads with analog input)
- Power (power supply)

Details about the pad properties are defined in the Electrical Parameters.

Table 6 Package Pin Mapping

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.0	23	17	13	15	7	STD_IN OUT	
P0.1	24	18	-	-	-	STD_IN OUT	
P0.2	25	19	-	-	-	STD_IN OUT	
P0.3	26	20	-	-	-	STD_IN OUT	
P0.4	27	21	14	-	-	STD_IN OUT	
P0.5	28	22	15	16	8	STD_IN OUT	
P0.6	29	23	16	17	9	STD_IN OUT	

General Device Information
Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.7	30	24	17	18	10	STD_IN OUT	
P0.8	33	27	18	19	11	STD_IN OUT	
P0.9	34	28	19	20	12	STD_IN OUT	
P0.10	35	29	20	-	-	STD_IN OUT	
P0.11	36	30	-	-	-	STD_IN OUT	
P0.12	37	31	21	21	-	STD_IN OUT	
P0.13	38	32	22	22	-	STD_IN OUT	
P0.14	39	33	23	23	13	STD_IN OUT	
P0.15	40	34	24	24	14	STD_IN OUT	
P1.0	22	16	12	14	-	High Current	
P1.1	21	15	11	13	-	High Current	
P1.2	20	14	10	12	-	High Current	
P1.3	19	13	9	11	-	High Current	
P1.4	18	12	-	-	-	High Current	
P1.5	17	11	-	-	-	High Current	
P1.6	16	-	-	-	-	STD_IN OUT	
P2.0	1	35	25	1	15	STD_IN OUT/AN	

Table 9 Port I/O Functions (cont'd)

Function	Outputs							Inputs								
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input	Input	Input
P2.6								ACMP1.I NN	VADC0. G0CH0		ERU0.2A 1	USIC0_C H0.DX3E	USIC0_C H0.DX4E	USIC0_C H1.DX5D	ORC4.AI N	
P2.7								ACMP1.I NP	VADC0. G1CH1		ERU0.3A 1	USIC0_C H0.DX5C	USIC0_C H1.DX3D	USIC0_C H1.DX4D	ORC5.AI N	
P2.8								ACMP0.I NN	VADC0. G0CH1	VADC0. G1CH0	ERU0.3B 1	USIC0_C H0.DX3D	USIC0_C H0.DX4D	USIC0_C H1.DX5C	ORC6.AI N	
P2.9								ACMP0.I NP	VADC0. G0CH2	VADC0. G1CH4	ERU0.3B 0	USIC0_C H0.DX5A	USIC0_C H1.DX3B	USIC0_C H1.DX4B	ORC7.AI N	
P2.10	ERU0. PDOUT1	CCU40. OUT2	ERU0. GOUT1		CCU80. OUT30	ACMP0. OUT	USIC0_C H1.DOUT 0		VADC0. G0CH3	VADC0. G1CH2	ERU0.2B 0	USIC0_C H0.DX3C	USIC0_C H0.DX4C	USIC0_C H1.DX0F		
P2.11	ERU0. PDOUT0	CCU40. OUT3	ERU0. GOUT0		CCU80. OUT31	USIC0_C H1.SCLK OUT	USIC0_C H1.DOUT 0	ACMP.RE F	VADC0. G0CH4	VADC0. G1CH3	ERU0.2B 1	USIC0_C H1.DX0E	USIC0_C H1.DX1E			

3 Electrical Parameters

This section provides the electrical parameters which are implementation-specific for the XMC1300.

3.1 General Parameters

3.1.1 Parameter Interpretation

The parameters listed in this section represent partly the characteristics of the XMC1300 and partly its requirements on the system. To aid interpreting the parameters easily when evaluating them for a design, they are indicated by the abbreviations in the "Symbol" column:

- **CC**
Such parameters indicate **C**ontroller **C**haracteristics, which are distinctive feature of the XMC1300 and must be regarded for a system design.
- **SR**
Such parameters indicate **S**ystem **R**equirements, which must be provided by the application system in which the XMC1300 is designed in.

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_{ST}	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on digital pins with respect to V_{SSP} ¹⁾	V_{IN}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Voltage on P2 pins with respect to V_{SSP} ²⁾	V_{INP2}	SR	-0.3	–	$V_{DDP} + 0.3$	V	–
Voltage on analog input pins with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	$V_{DDP} + 0.5$ or max. 6	V	whichever is lower
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute maximum sum of all input currents during overload condition	ΣI_{IN}	SR	-50	–	+50	mA	–

1) Excluding port pins P2.[1,2,6,7,8,9,11].

2) Applicable to port pins P2.[1,2,6,7,8,9,11].

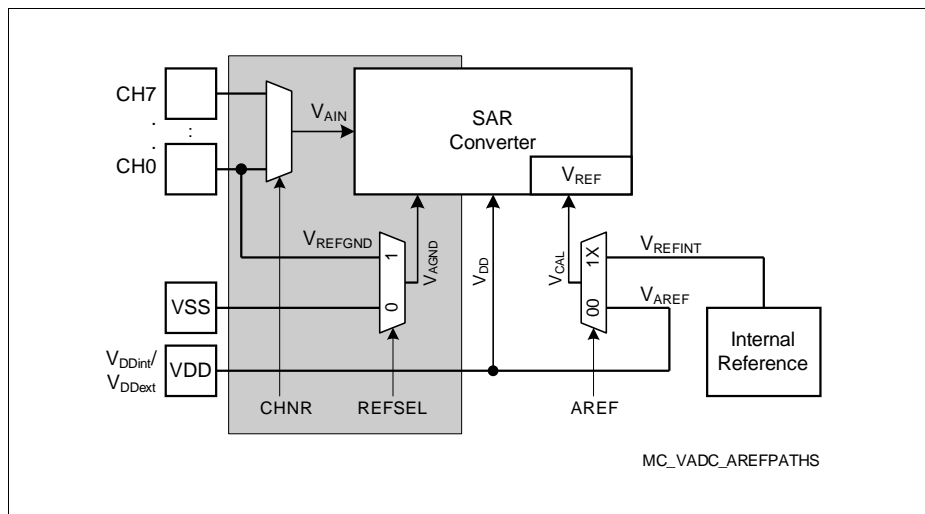


Figure 11 ADC Voltage Supply

3.2.3 Out of Range Comparator (ORC) Characteristics

The Out-of-Range Comparator (ORC) triggers on analog input voltages (V_{AIN}) above the V_{DDP} on selected input pins (ORCx.AIN) and generates a service request trigger (ORCx.OUT).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 18 Out of Range Comparator (ORC) Characteristics (Operating Conditions apply; $V_{DDP} = 3.0\text{ V} - 5.5\text{ V}$; $C_L = 0.25\text{ pF}$)

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
DC Switching Level	V_{ODC}	CC	54	—	183	mV	$V_{AIN} \geq V_{DDP} + V_{ODC}$
Hysteresis	V_{OHYS}	CC	15	—	54	mV	
Always detected Overvoltage Pulse	t_{OPDD}	CC	103	—	—	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			88	—	—	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Never detected Overvoltage Pulse	t_{OPDN}	CC	—	—	21	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			—	—	11	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Detection Delay of a persistent Overvoltage	t_{ODD}	CC	39	—	132	ns	$V_{AIN} \geq V_{DDP} + 150\text{ mV}$
			31	—	121	ns	$V_{AIN} \geq V_{DDP} + 350\text{ mV}$
Release Delay	t_{ORD}	CC	44	—	240	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 5\text{ V}$
			57	—	340	ns	$V_{AIN} \leq V_{DDP}$; $V_{DDP} = 3.3\text{ V}$
Enable Delay	t_{OED}	CC	—	—	300	ns	ORCCTRL.ENORCx = 1

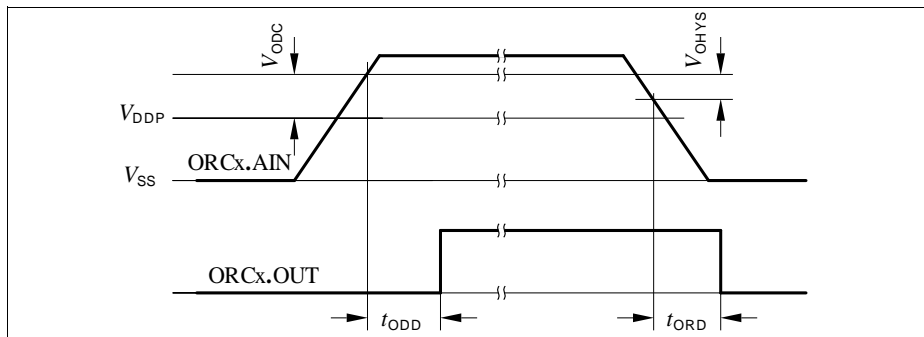


Figure 12 ORCx.OUT Trigger Generation

3.2.6 Power Supply Current

The total power supply current defined below consists of a leakage and a switching component.

Application relevant values are typically lower than those given in the following tables, and depend on the customer's system operating conditions (e.g. thermal connection or used application configurations).

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 21 Power Supply Parameters; $V_{DDP} = 5V$

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min	Typ. ¹⁾	Max.		
Active mode current Peripherals enabled f_{MCLK} / f_{PCLK} in MHz ²⁾	I_{DDPAE} CC	–	9.2	12	mA	32 / 64
		–	8.1	-	mA	24 / 48
		–	6.6	-	mA	16 / 32
		–	5.5	-	mA	8 / 16
		–	4	-	mA	1 / 1
Active mode current Peripherals disabled f_{MCLK} / f_{PCLK} in MHz ³⁾	I_{DDPAD} CC	–	4.8	-	mA	32 / 64
		–	4.1	-	mA	24 / 48
		–	3.3	-	mA	16 / 32
		–	2.7	-	mA	8 / 16
		–	1.5	-	mA	1 / 1
Active mode current Code execution from RAM Flash is powered down f_{MCLK} / f_{PCLK} in MHz	I_{DDPAR} CC	–	7.3	-	mA	32 / 64
		–	6.3	-	mA	24 / 48
		–	5.2	-	mA	16 / 32
		–	4.2	-	mA	8 / 16
		–	3.3	-	mA	1 / 1
Sleep mode current Peripherals clock enabled f_{MCLK} / f_{PCLK} in MHz ⁴⁾	I_{DDPSE} CC	–	6.6	-	mA	32 / 64
			5.8	-	mA	24 / 48
			5.1	-	mA	16 / 32
			4.4	-	mA	8 / 16
			3.7	-	mA	1 / 1

Electrical Parameters
Table 21 Power Supply Parameters; $V_{DDP} = 5V$

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min	Typ. ¹⁾	Max.		
Sleep mode current Peripherals clock disabled Flash active f_{MCLK} / f_{PCLK} in MHz ⁵⁾	I_{DDPSD} CC	–	1.8	-	mA	32 / 64
			1.7	-	mA	24 / 48
			1.6	-	mA	16 / 32
			1.5	-	mA	8 / 16
			1.4	-	mA	1 / 1
Sleep mode current Peripherals clock disabled Flash powered down f_{MCLK} / f_{PCLK} in MHz ⁶⁾	I_{DDPSR} CC	–	1.2	-	mA	32 / 64
			1.1	-	mA	24 / 48
			1.0	-	mA	16 / 32
			0.8	-	mA	8 / 16
			0.7	-	mA	1 / 1
Deep Sleep mode current ⁷⁾	I_{DDPDS} CC	–	0.24	-	mA	
Wake-up time from Sleep to Active mode ⁸⁾	t_{SSA} CC	–	6	-	cycles	
Wake-up time from Deep Sleep to Active mode ⁹⁾	t_{DSA} CC	–	280	-	μsec	

1) The typical values are measured at $T_A = +25\text{ °C}$ and $V_{DDP} = 5V$.

2) CPU and all peripherals clock enabled, Flash is in active mode.

3) CPU enabled, all peripherals clock disabled, Flash is in active mode.

4) CPU in sleep, all peripherals clock enabled and Flash is in active mode.

5) CPU in sleep, Flash is in active mode.

6) CPU in sleep, Flash is powered down and code executed from RAM after wake-up.

7) CPU in sleep, peripherals clock disabled, Flash is powered down and code executed from RAM after wake-up.

8) CPU in sleep, Flash is in active mode during sleep mode.

9) CPU in sleep, Flash is in powered down mode during deep sleep mode.

Electrical Parameters

Table 22 provides the active current consumption of some modules operating at 5 V power supply at 25° C. The typical values shown are used as a reference guide on the current consumption when these modules are enabled.

Table 22 Typical Active Current Consumption

Active Current Consumption	Symbol	Limit Values	Unit	Test Condition
		Typ.		
Baseload current	I_{CPUDDC}	5.04	mA	Modules including Core, SCU, PORT, memories, ANATOP ¹⁾
VADC and SHS	I_{ADCDDC}	3.4	mA	Set CGATCLR0.VADC to 1 ²⁾
USIC0	$I_{USIC0DDC}$	0.87	mA	Set CGATCLR0.USIC0 to 1 ³⁾
CCU40	$I_{CCU40DDC}$	0.94	mA	Set CGATCLR0.CCU40 to 1 ⁴⁾
CCU80	$I_{CCU80DDC}$	0.42	mA	Set CGATCLR0.CCU80 to 1 ⁵⁾
POSIF0	$I_{PIF0DDC}$	0.26	mA	Set CGATCLR0.POSIF0 to 1 ⁶⁾
BCCU0	$I_{BCCU0DDC}$	0.24	mA	Set CGATCLR0.BCCU0 to 1 ⁷⁾
MATH	$I_{MATHDDC}$	0.35	mA	Set CGATCLR0.MATH to 1 ⁸⁾
WDT	I_{WDTDDC}	0.03	mA	Set CGATCLR0.WDT to 1 ⁹⁾
RTC	I_{RTCDDC}	0.01	mA	Set CGATCLR0.RTC to 1 ¹⁰⁾

1) Baseload current is measured with device running in user mode, MCLK=PCLK=32 MHz, with an endless loop in the flash memory. The clock to the modules stated in CGATSTAT0 are gated.

2) Active current is measured with: module enabled, MCLK=32 MHz, running in auto-scan conversion mode

3) Active current is measured with: module enabled, alternating messages sent to PC at 57.6kbaud every 200ms

4) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU4 slice for PWM switching from 1500Hz and 1000Hz at regular intervals, 1 CCU4 slice in capture mode for reading period and duty cycle

5) Active current is measured with: module enabled, MCLK=PCLK=32 MHz, 1 CCU8 slice with PWM frequency at 1500Hz and a period match interrupt used to toggle duty cycle between 10% and 90%

6) Active current is measured with: module enabled, MCLK=32 MHz, PCLK=64MHz, hall sensor mode

7) Active current is measured with: module enabled, MCLK=32 MHz, PCLK=64MHz, FCLK=0.8MHz, Normal mode (BCCU Clk = FCLK/4), 3 BCCU Channels and 1 Dimming Engine, change color or dim every 1s

8) Active current is measured with: module enabled, MCLK=32 MHz, PCLK=64MHz, tangent calculation in while loop; CORDIC circular rotation, no keep, autostart; 32-by-32 bit signed DIV, autostart, DVS right shift by 11

9) Active current is measured with: module enabled, MCLK=32 MHz, time-out mode; WLB = 0, WUB = 0x00008000; WDT serviced every 1s

10) Active current is measured with: module enabled, MCLK=32 MHz, Periodic interrupt enabled

3.2.7 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase Time per page / sector	$t_{\text{ERASE CC}}$	6.8	7.1	7.6	ms	
Program time per block	$t_{\text{PSER CC}}$	102	152	204	μs	
Wake-Up time	$t_{\text{WU CC}}$	–	32.2	–	μs	
Read time per word	$t_{\text{a CC}}$	–	50	–	ns	
Data Retention Time	$t_{\text{RET CC}}$	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States ¹⁾	$N_{\text{WSFLASH CC}}$	0	0	0		$f_{\text{MCLK}} = 8 \text{ MHz}$
		0	1	1		$f_{\text{MCLK}} = 16 \text{ MHz}$
		1	1.3	2		$f_{\text{MCLK}} = 32 \text{ MHz}$
Fixed Flash Wait States configured in bit NVM_NVMCONF.WS	$N_{\text{FWSFLASH SR}}$	0	0	1		NVM_CONFIG1.FI XWS = 1 _B , $f_{\text{MCLK}} \leq 16 \text{ MHz}$
		1	1	1		NVM_CONFIG1.FI XWS = 1 _B , $16 \text{ MHz} < f_{\text{MCLK}} \leq 32 \text{ MHz}$
Erase Cycles	$N_{\text{ECYC CC}}$	–	–	5*10 ⁴	cycles	Sum of page and sector erase cycles
Total Erase Cycles	$N_{\text{TECYC CC}}$	–	–	2*10 ⁶	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

Electrical Parameters

Figure 20 shows the typical curves for the accuracy of DCO1, with and without calibration based on temperature sensor, respectively.

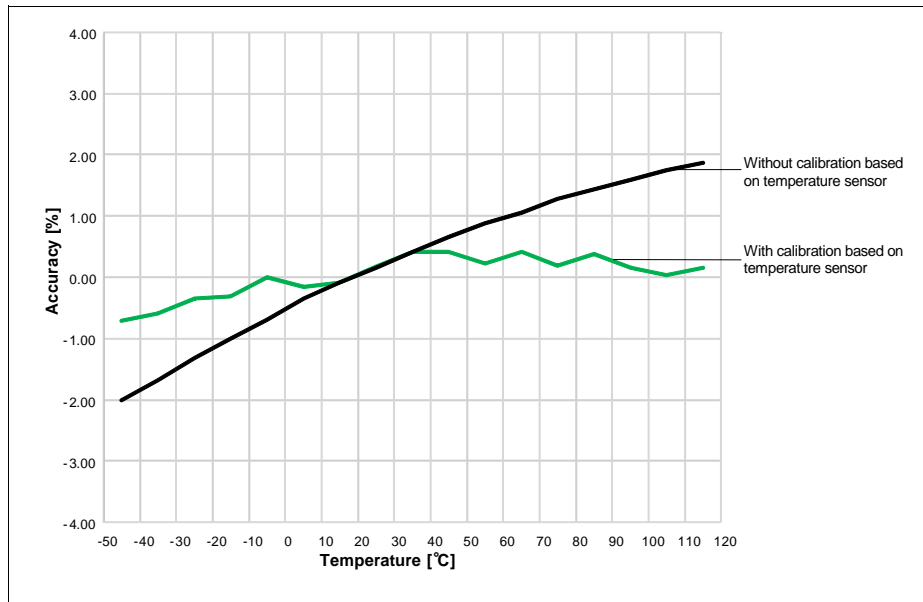


Figure 20 Typical DCO1 accuracy over temperature

Table 26 provides the characteristics of the 32 kHz clock output from digital controlled oscillators, DCO2 in XMC1300.

Table 26 32 kHz DCO2 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	–	32.75	–	kHz	under nominal conditions ¹⁾ after trimming
Accuracy	Δf_{LT}	CC	-1.7	–	3.4	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (0 °C to 85 °C)
			-3.9	–	4.0	%	with respect to $f_{\text{NOM}}(\text{typ})$, over temperature (-40 °C to 105 °C)

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and $T_{\text{A}} = + 25\text{ °C}$.

3.3.4 Serial Wire Debug Port (SW-DP) Timing

The following parameters are applicable for communication through the SW-DP interface.

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 27 SWD Interface Timing Parameters(Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
SWDCLK high time	t_1 SR	50	—	500000	ns	—
SWDCLK low time	t_2 SR	50	—	500000	ns	—
SWDIO input setup to SWDCLK rising edge	t_3 SR	10	—	—	ns	—
SWDIO input hold after SWDCLK rising edge	t_4 SR	10	—	—	ns	—
SWDIO output valid time after SWDCLK rising edge	t_5 CC	—	—	68	ns	$C_L = 50$ pF
		—	—	62	ns	$C_L = 30$ pF
SWDIO output hold time from SWDCLK rising edge	t_6 CC	4	—	—	ns	

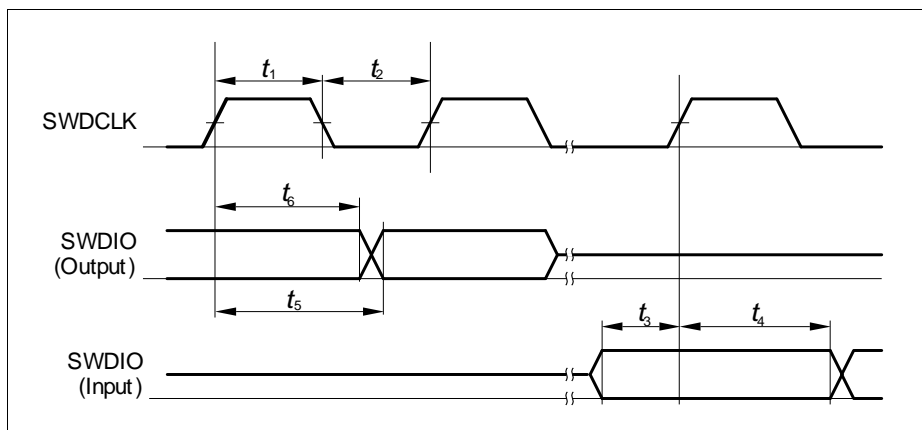


Figure 21 SWD Timing

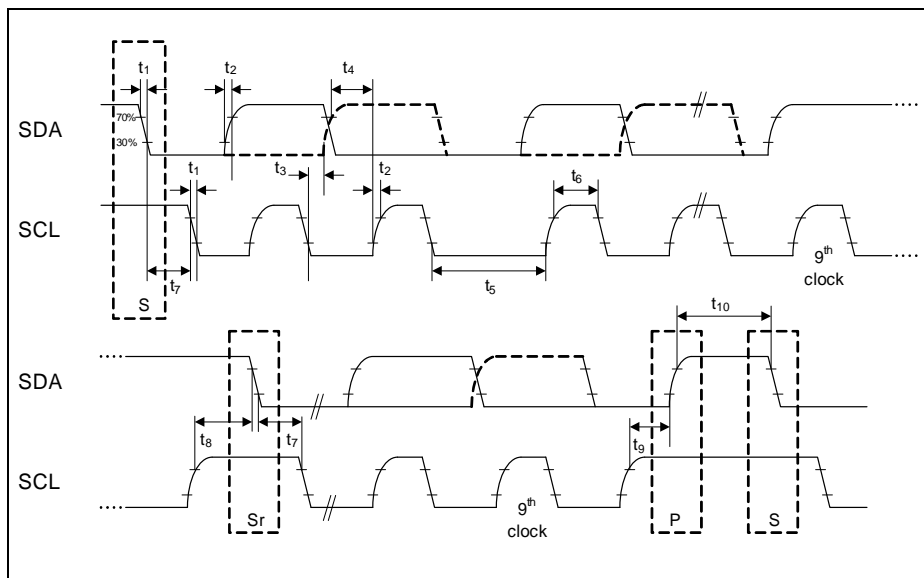


Figure 23 USIC IIC Stand and Fast Mode Timing

3.3.6.3 Inter-IC Sound (IIS) Interface Timing

The following parameters are applicable for a USIC channel operated in IIS mode.

Note: Operating Conditions apply.

Table 33 USIC IIS Master Transmitter Timing

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Clock period	t_1 CC	$2/f_{MCLK}$	-	-	ns	$V_{DDP} \geq 3\text{ V}$
		$4/f_{MCLK}$	-	-	ns	$V_{DDP} < 3\text{ V}$
Clock HIGH	t_2 CC	$0.35 \times t_{1min}$	-	-	ns	
Clock Low	t_3 CC	$0.35 \times t_{1min}$	-	-	ns	
Hold time	t_4 CC	0	-	-	ns	
Clock rise time	t_5 CC	-	-	$0.15 \times t_{1min}$	ns	

4.2 Package Outlines

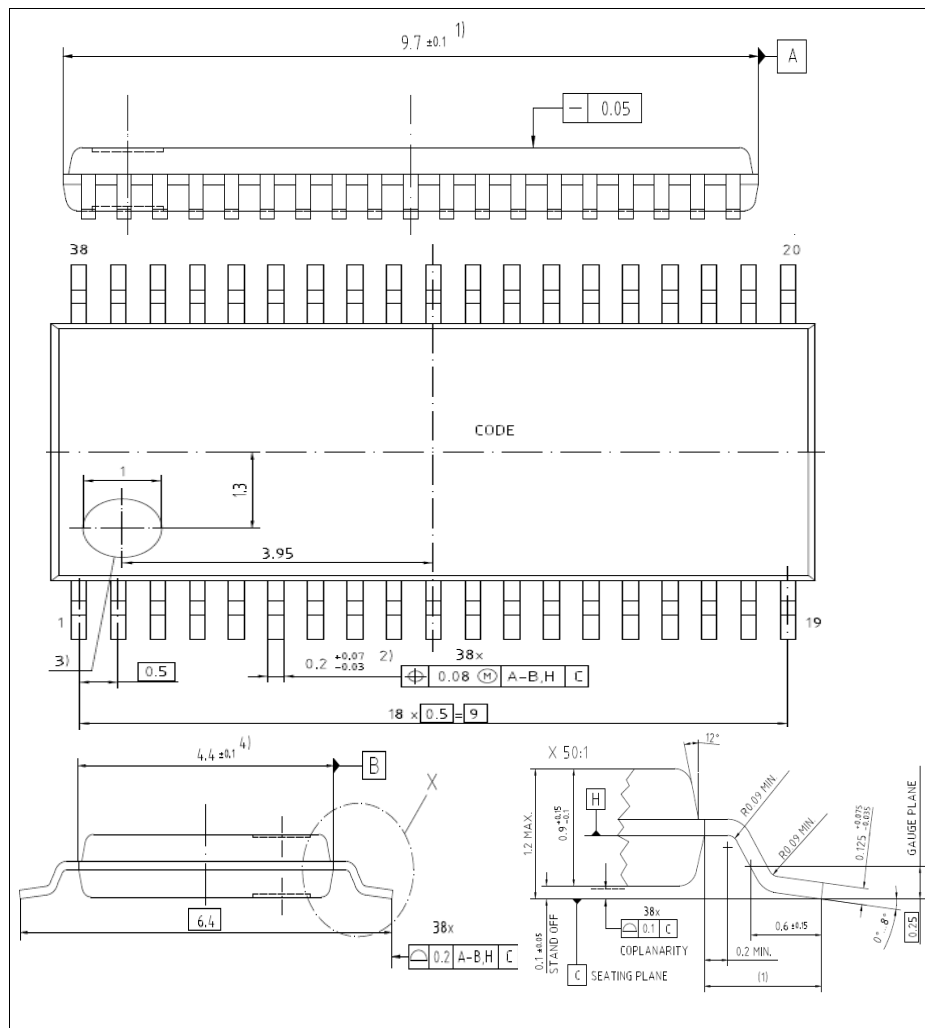


Figure 26 PG-TSSOP-38-9